

# **HEXFET® POWER MOSFET**

## **IRFN9140**

## **N-CHANNEL**

## -100 Volt, 0.20Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-establish advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits.

The Surface Mount Device (SMD-1) package represents another step in the continual evolution of surface mount technology. The SMD-1 will give designers the extra flexibility they need to increase circuit board density. International Rectifier has engineered the SMD-1 package to meet the specific needs of the power market by increasing the size of the termination pads, thereby enhancing thermal and electrical performance.

## **Product Summary**

Part Number	BVDSS	RDS(on)	lb
IRFN9140	-100V	0.20Ω	-18A

### Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Surface Mount
- Light-weight

# **Absolute Maximum Ratings**

	Parameter	IRFN9140	Units
ID @ VGS = -10V, TC = 25°C	Continuous Drain Current	-18	
$I_D @ V_{GS} = -10V, T_C = 100^{\circ}C$	Continuous Drain Current	-11	A
IDM	Pulsed Drain Current ①	-72	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Max. Power Dissipation	125	W
	Linear Derating Factor	1.0	W/K ®
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	500	mJ
IAR	Avalanche Current ①	-18	Α
EAR	Repetitive Avalanche Energy ①	12.5	mJ
dv/dt	Peak Diode Recovery dv/dt ®	-5.0	V/ns
TJ	Operating Junction	-55 to 150	
TSTG	Storage Temperature Range		°C
	Package Mounting Surface Temperature	300 (for 5 seconds)	
	Weight	2.6 (typical)	g

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# Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

	Parameter	Min.	Тур.	Max.	Units	Test Co	nditions
BVDSS	Drain-to-Source Breakdown Voltage	-100	_		V	VGS = 0V, ID = -1.0mA	
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Temperature Coefficient of Breakdown Voltage	_	-0.087		V/°C	Reference to 25°C, I <sub>D</sub> = -1.0mA	
RDS(on)	Static Drain-to-Source	_	_	0.20		VGS = -10	)V, ID = -11A4
	On-State Resistance	_	_	0.22	Ω	VGS = -10	V, ID = -18A
VGS(th)	Gate Threshold Voltage	-2.0	_	-4.0	V	VDS = VGS	S, ID = -250μA
gfs	Forward Transconductance	6.2	_	_	S (U)	VDS > -15V	IDS = -11A @
IDSS	Zero Gate Voltage Drain Current	_	_	-25	_	VDS = 0.8 x Max	k Rating, $V$ GS = $0V$
	·	_	_	-250	μΑ	VDS = 0.8	x Max Rating
						VGS = 0V	, TJ = 125°C
IGSS	Gate-to-Source Leakage Forward	_	_	-100	nA	VGS = -20V	
IGSS	Gate-to-Source Leakage Reverse	_	_	100	1171	VGS = 20V	
Qg	Total Gate Charge	31	_	60		VGS = -10V, ID = -18A	
Qgs	Gate-to-Source Charge	3.7	_	13	nC	VDS = Max	Rating x 0.5
Qgd	Gate-to-Drain ("Miller") Charge	7.0		35.2		see figure	es 6 and 13
td(on)	Turn-On Delay Time	_	_	35		VDD = -50	)V, ID = -18A,
tr	Rise Time	_	_	85	ns	RG = 9.1Ω, VGS = -10V	
td(off)	Turn-Off Delay Time	_	_	85	115		
tf	FallTime	_	_	65		see figure 10	
LD	Internal Drain Inductance	_	2.0		nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.	Modified MOSFET symbol showing the internal inductances.
LS	Internal Source Inductance	_	4.1	_	1111	Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.	
C <sub>iss</sub>	Input Capacitance	_	1400			Vgs = 0V,	V <sub>DS</sub> = -25V
Coss	Output Capacitance		600	_	pF	f = 1	.0 MHz
C <sub>rss</sub>	Reverse Transfer Capacitance	_	200			see figure 5	

# **Source-Drain Diode Ratings and Characteristics**

	Parameter		Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)		_	_	-18	Α	Modified MOSFET symbol showing the
ISM	Pulse Source Current (Body Diode) ①		_	_	-72		integral reverse p-n junction rectifier.
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VSD	Diode Forward Voltage		_	_	-4.2	V	Tj = 25°C, IS = -18A, VGS = 0V ④
t <sub>rr</sub>	Reverse Recovery Time		_	_	280	ns	Tj = 25°C, IF = -18A, di/dt ≤ -100A/μs
QRR	Reverse Recovery Charge		_	_	3.6	μC	V <sub>DD</sub> ≤ -50V ④
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by LS + LD.					

# **Thermal Resistance**

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R <sub>th</sub> JC	Junction-to-Case	_	_	1.0		
R <sub>thJ-PCB</sub>	Junction-to-PC Board	_	TBD	_	K/W	Soldered to a copper clad PC board

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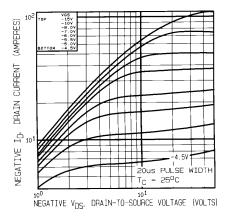


Fig. 1 — Typical Output Characteristics  $T_C = 25$ °C

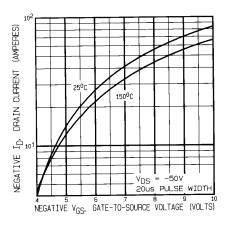


Fig. 3 — Typical Transfer Characteristics

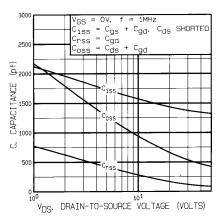


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

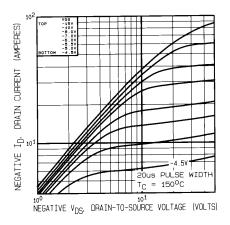


Fig. 2 — Typical Output Characteristics  $T_C = 150^{\circ}C$ 

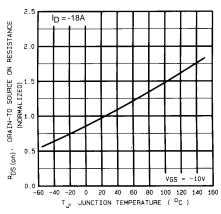


Fig. 4 — Normalized On-Resistance Vs.Temperature

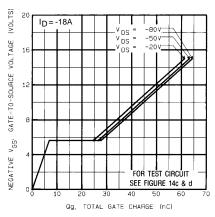


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source  ${}^{\mbox{Voltage}}_{\mbox{WWW.DataSheet 4U.com}}$ 

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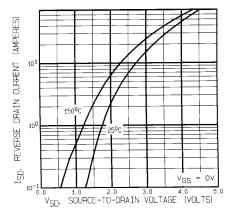


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

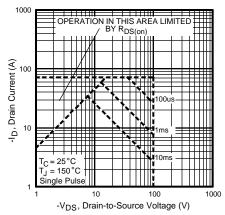


Fig. 8 — Maximum Safe Operating Area

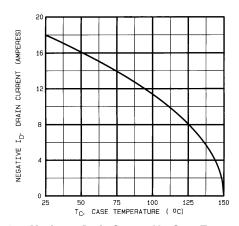


Fig. 9 — Maximum Drain Current Vs. Case Temperature

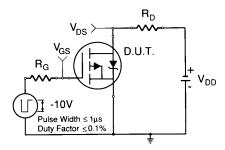


Fig. 10a — Switching Time Test Circuit

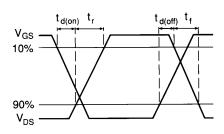


Fig. 10b — Switching Time Waveforms

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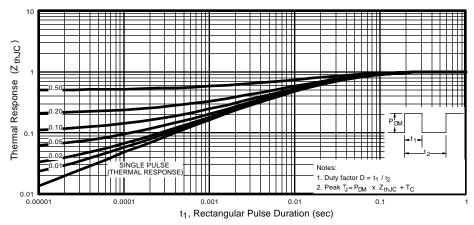


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

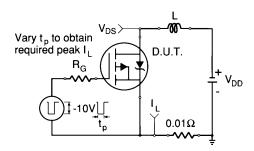


Fig. 12a — Unclamped Inductive Test Circuit

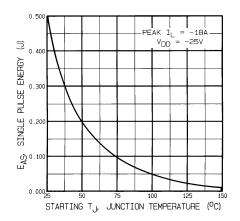


Fig. 12c — Max. Avalanche Energy vs. Current

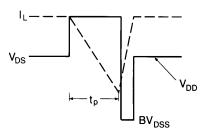


Fig. 12b — Unclamped Inductive Waveforms

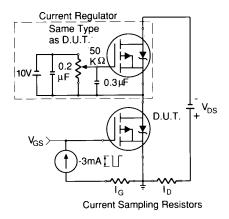


Fig. 13a — Gate Charam Tepfata Shitet 4U.com

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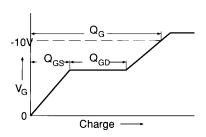
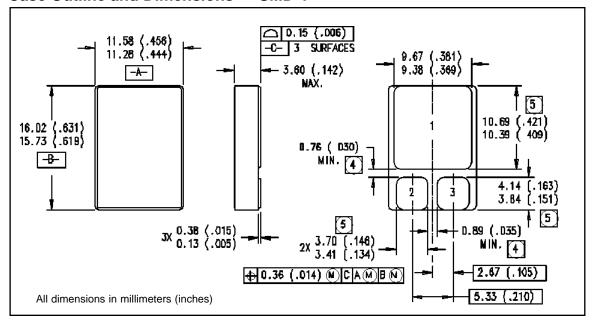


Fig. 13b — Basic Gate Charge Waveform

- Repetitive Rating; Pulse width limited by maximum junction temperature. (see figure 11)
- ② @ V<sub>DD</sub> = -25V, Starting T<sub>J</sub> = 25°C, E<sub>AS</sub> = [0.5 \* L \* (I<sub>L</sub><sup>2</sup>) \* [BV<sub>DSS</sub>/(BV<sub>DSS</sub>-V<sub>DD</sub>)] Peak I<sub>L</sub> = -18A, V<sub>GS</sub> = -10V, 25 ≤ R<sub>G</sub> ≤ 200Ω
- ③  $I_{SD} \le 1 18A$ ,  $di/dt \le -100A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ ,  $T_{J} \le 150$ °C
- ⓐ Pulse width ≤ 300  $\mu$ s; Duty Cycle ≤ 2%
- ⑤ K/W = °C/W W/K = W/°C

# Case Outline and Dimensions — SMD-1



# International TOR Rectifier

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